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### Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### **Applications of Embedded - FPGAs**

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

#### **Details**

Product Status	Active
Number of LABs/CLBs	1879
Number of Logic Elements/Cells	24051
Total RAM Bits	958464
Number of I/O	186
Number of Gates	-
Voltage - Supply	1.14V ~ 1.26V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	256-LBGA
Supplier Device Package	256-FTBGA (17x17)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/xilinx/xc6slx25-3ftg256c">https://www.e-xfl.com/product-detail/xilinx/xc6slx25-3ftg256c</a>

## SelectIO™ Interface DC Input and Output Levels

Table 7: Recommended Operating Conditions for User I/Os Using Single-Ended Standards

I/O Standard	$V_{CCO}$ for Drivers <sup>(1)</sup>			$V_{REF}$ for Inputs		
	$V$ , Min	$V$ , Nom	$V$ , Max	$V$ , Min	$V$ , Nom	$V$ , Max
LV TTL	3.0	3.3	3.45			
LVC MOS33	3.0	3.3	3.45			
LVC MOS25	2.3	2.5	2.7			
LVC MOS18	1.65	1.8	1.95			
LVC MOS18_JEDEC	1.65	1.8	1.95			
LVC MOS15	1.4	1.5	1.6			
LVC MOS15_JEDEC	1.4	1.5	1.6			
LVC MOS12	1.1	1.2	1.3			
LVC MOS12_JEDEC	1.1	1.2	1.3			
PCI33_3 <sup>(2)</sup>	3.0	3.3	3.45			
PCI66_3 <sup>(2)</sup>	3.0	3.3	3.45			
I2C	2.7	3.0	3.45			
SMBUS	2.7	3.0	3.45			
SDIO	3.0	3.3	3.45			
MOBILE_DDR	1.7	1.8	1.9			
HSTL_I	1.4	1.5	1.6	0.68	0.75	0.9
HSTL_II	1.4	1.5	1.6	0.68	0.75	0.9
HSTL_III	1.4	1.5	1.6	–	0.9	–
HSTL_I_18	1.7	1.8	1.9	0.8	0.9	1.1
HSTL_II_18	1.7	1.8	1.9	–	0.9	–
HSTL_III_18	1.7	1.8	1.9	–	1.1	–
SSTL3_I	3.0	3.3	3.45	1.3	1.5	1.7
SSTL3_II	3.0	3.3	3.45	1.3	1.5	1.7
SSTL2_I	2.3	2.5	2.7	1.13	1.25	1.38
SSTL2_II	2.3	2.5	2.7	1.13	1.25	1.38
SSTL18_I	1.7	1.8	1.9	0.833	0.9	0.969
SSTL18_II	1.7	1.8	1.9	0.833	0.9	0.969
SSTL15_II	1.425	1.5	1.575	0.69	0.75	0.81

**Notes:**

- $V_{CCO}$  range required when using I/O standard for an output. Also required for MOBILE\_DDR, PCI33\_3, LVC MOS18\_JEDEC, LVC MOS15\_JEDEC, and LVC MOS12\_JEDEC inputs, and for LVC MOS25 inputs when  $V_{CCAUX} = 3.3V$ .
- For PCI systems, the transmitter and receiver should have common supplies for  $V_{CCO}$ .

## GTP Transceiver DC Input and Output Levels

Table 16 summarizes the DC output specifications of the GTP transceivers in Spartan-6 FPGAs. Figure 1 shows the single-ended output voltage swing. Figure 2 shows the peak-to-peak differential output voltage.

Consult [UG386: Spartan-6 FPGA GTP Transceivers User Guide](#) for further details.

Table 16: GTP Transceiver DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
DV <sub>PPIN</sub>	Differential peak-to-peak input voltage	External AC coupled	140	—	2000	mV
V <sub>IN</sub>	Absolute input voltage	DC coupled MGTAVTTRX = 1.2V	-400	—	MGTAVTTRX	mV
V <sub>CMIN</sub>	Common mode input voltage	DC coupled MGTAVTTRX = 1.2V	—	3/4 MGTAVTTRX	—	mV
DV <sub>PPOUT</sub>	Differential peak-to-peak output voltage <sup>(1)</sup>	Transmitter output swing is set to maximum setting	—	—	1000	mV
V <sub>SEOUT</sub>	Single-ended output voltage <sup>(1)</sup>	—	—	—	500	mV
V <sub>CMOUTDC</sub>	Common mode output voltage	Equation based	MGTAVTTX - V <sub>SEOUT</sub> /2			mV
R <sub>IN</sub>	Differential input resistance	—	80	100	130	Ω
R <sub>OUT</sub>	Differential output resistance	—	80	100	130	Ω
T <sub>OSKEW</sub>	Transmitter output skew	—	—	—	15	ps
C <sub>EXT</sub>	Recommended external AC coupling capacitor <sup>(2)</sup>	—	75	100	200	nF

**Notes:**

- The output swing and preemphasis levels are programmable using the attributes discussed in [UG386: Spartan-6 FPGA GTP Transceivers User Guide](#) and can result in values lower than reported in this table.
- Other values can be used as appropriate to conform to specific protocols and standards.

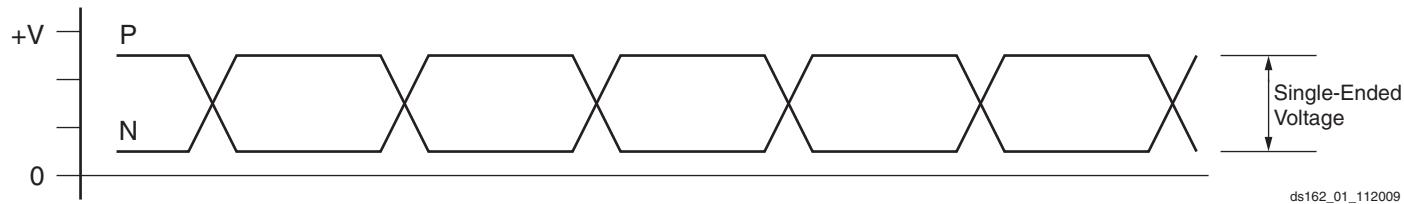


Figure 1: Single-Ended Peak-to-Peak Voltage

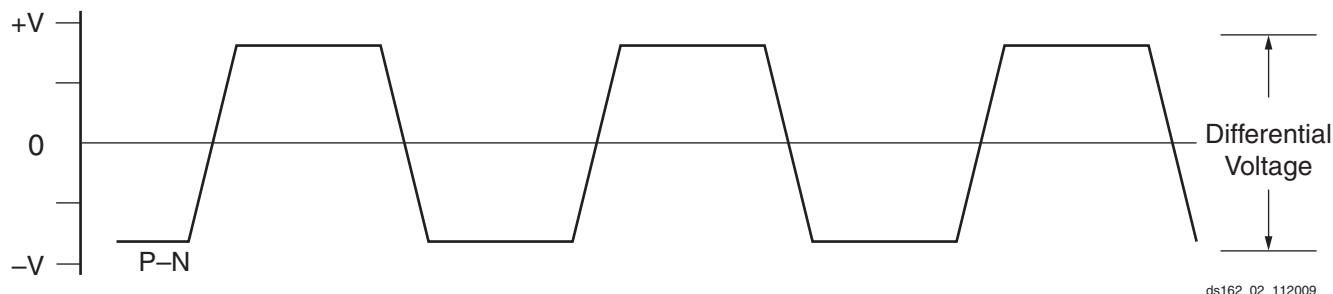


Figure 2: Differential Peak-to-Peak Voltage

Table 17 summarizes the DC specifications of the clock input of the GTP transceiver. Consult [UG386: Spartan-6 FPGA GTP Transceivers User Guide](#) for further details.

## Performance Characteristics

This section provides the performance characteristics of some common functions and designs implemented in Spartan-6 devices. The numbers reported here are worst-case values; they have all been fully characterized. These values are subject to the same guidelines as the [Switching Characteristics, page 19](#).

**Table 25: Interface Performances**

<b>Description</b>	<b>I/O Resource</b>	<b>Clock Buffer</b>	<b>Data Width</b>	<b>Speed Grade</b>				<b>Units</b>		
				<b>-3</b>	<b>-3N</b>	<b>-2</b>	<b>-1L</b>			
<b>Networking Applications<sup>(1)</sup></b>										
SDR LVDS transmitter or receiver	IOB SDR register	BUFG	—	400	400	375	250	Mb/s		
DDR LVDS transmitter or receiver	ODDR2/IDDR2 register	2 BUFGs	—	800	800	750	500	Mb/s		
SDR LVDS transmitter	OSERDES2	BUFPLL	2	500	500	500	250	Mb/s		
			3	750	750	750	375	Mb/s		
			4-8	1080	1050	950	500	Mb/s		
DDR LVDS transmitter	OSERDES2	2 BUFIO2s	2	500	500	500	250	Mb/s		
			3	750	750	750	375	Mb/s		
			4-8	1080	1050	950	500	Mb/s		
SDR LVDS receiver	ISERDES2 in RETIMED mode	BUFPLL	2	500	500	500	—	Mb/s		
			3	750	750	750	—	Mb/s		
			4-8	1080	1050	950	—	Mb/s		
DDR LVDS receiver	ISERDES2 in RETIMED mode	2 BUFIO2s	2	500	500	500	—	Mb/s		
			3	750	750	750	—	Mb/s		
			4-8	1080	1050	950	—	Mb/s		
<b>Memory Interfaces (Implemented using the Spartan-6 FPGA Memory Controller Block)<sup>(2)</sup></b>										
<b>Standard Performance (Standard V<sub>CCINT</sub>)</b>										
DDR				400	<a href="#">Note 4</a>	400	350	Mb/s		
DDR2				667	<a href="#">Note 4</a>	625	400	Mb/s		
DDR3				800	<a href="#">Note 4</a>	667	—	Mb/s		
LPDDR (Mobile_DDR)				400	<a href="#">Note 4</a>	400	350	Mb/s		
<b>Extended Performance (Requires Extended Performance V<sub>CCINT</sub>)<sup>(3)</sup></b>										
DDR2				800	<a href="#">Note 4</a>	667	—	Mb/s		

**Notes:**

- Refer to [XAPP1064](#), *Source-Synchronous Serialization and Deserialization (up to 1050 Mb/s)* and [UG381](#), *Spartan-6 FPGA SelectIO Resources User Guide*.
- Refer to [UG388](#), *Spartan-6 FPGA Memory Controller User Guide*.
- Extended Memory Controller block performance for DDR2 can be achieved using the extended performance V<sub>CCINT</sub> range from [Table 2](#).
- The LX4 device, all devices in the TQG144 and CPG196 packages, and the -3N speed grade do not support a Memory Controller Block.

Table 28: IOB Switching Characteristics for the Commercial (XC) Spartan-6 Devices (Cont'd)

I/O Standard	T <sub>IOPI</sub>				T <sub>IOOP</sub>				T <sub>IOTP</sub>				Units	
	Speed Grade				Speed Grade				Speed Grade					
	-3	-3N	-2	-1L <sup>(1)</sup>	-3	-3N	-2	-1L <sup>(1)</sup>	-3	-3N	-2	-1L <sup>(1)</sup>		
PPDS_33	1.17	1.29	1.42	1.68	1.57	1.71	1.91	2.43	3000	3000	3000	3000	ns	
PPDS_25	1.01	1.13	1.26	1.56	1.68	1.82	2.02	2.47	3000	3000	3000	3000	ns	
PCI33_3	1.07	1.19	1.32	1.57 <sup>(2)</sup>	3.51	3.65	3.85	4.38 <sup>(2)</sup>	3.51	3.65	3.85	4.38 <sup>(1)</sup>	ns	
PCI66_3	1.07	1.19	1.32	1.57 <sup>(2)</sup>	3.53	3.67	3.87	4.39 <sup>(2)</sup>	3.53	3.67	3.87	4.39 <sup>(1)</sup>	ns	
DISPLAY_PORT	1.02	1.14	1.27	1.56	3.15	3.29	3.49	4.08	3.15	3.29	3.49	4.08	ns	
I2C	1.33	1.45	1.58	1.82	11.56	11.70	11.90	12.52	11.56	11.70	11.90	12.52	ns	
SMBUS	1.33	1.45	1.58	1.82	11.56	11.70	11.90	12.52	11.56	11.70	11.90	12.52	ns	
SDIO	1.36	1.48	1.61	1.84	2.64	2.78	2.98	3.60	2.64	2.78	2.98	3.60	ns	
MOBILE_DDR	0.94	1.06	1.19	1.43	2.35	2.49	2.69	3.31	2.35	2.49	2.69	3.31	ns	
HSTL_I	0.90	1.02	1.15	1.39	1.66	1.80	2.00	2.62	1.66	1.80	2.00	2.62	ns	
HSTL_II	0.91	1.03	1.16	1.40	1.72	1.86	2.06	2.68	1.72	1.86	2.06	2.68	ns	
HSTL_III	0.95	1.07	1.20	1.44	1.67	1.81	2.01	2.61	1.67	1.81	2.01	2.61	ns	
HSTL_I_18	0.94	1.06	1.19	1.43	1.77	1.91	2.11	2.73	1.77	1.91	2.11	2.73	ns	
HSTL_II_18	0.94	1.06	1.19	1.43	1.85	1.99	2.19	2.81	1.85	1.99	2.19	2.81	ns	
HSTL_III_18	0.99	1.11	1.24	1.47	1.79	1.93	2.13	2.72	1.79	1.93	2.13	2.72	ns	
SSTL3_I	1.58	1.70	1.83	2.16	1.83	1.97	2.17	2.72	1.83	1.97	2.17	2.72	ns	
SSTL3_II	1.58	1.70	1.83	2.16	2.01	2.15	2.35	2.94	2.01	2.15	2.35	2.94	ns	
SSTL2_I	1.30	1.42	1.55	1.87	1.77	1.91	2.11	2.69	1.77	1.91	2.11	2.69	ns	
SSTL2_II	1.30	1.42	1.55	1.88	1.86	2.00	2.20	2.82	1.86	2.00	2.20	2.82	ns	
SSTL18_I	0.92	1.04	1.17	1.41	1.63	1.77	1.97	2.59	1.63	1.77	1.97	2.59	ns	
SSTL18_II	0.92	1.04	1.17	1.41	1.66	1.80	2.00	2.62	1.66	1.80	2.00	2.62	ns	
SSTL15_II	0.92	1.04	1.17	1.41	1.67	1.81	2.01	2.63	1.67	1.81	2.01	2.63	ns	
DIFF_HSTL_I	0.94	1.06	1.19	1.46	1.77	1.91	2.11	2.62	1.77	1.91	2.11	2.62	ns	
DIFF_HSTL_II	0.93	1.05	1.18	1.45	1.72	1.86	2.06	2.54	1.72	1.86	2.06	2.54	ns	
DIFF_HSTL_III	0.93	1.05	1.18	1.46	1.69	1.83	2.03	2.53	1.69	1.83	2.03	2.53	ns	
DIFF_HSTL_I_18	0.97	1.09	1.22	1.50	1.79	1.93	2.13	2.63	1.79	1.93	2.13	2.63	ns	
DIFF_HSTL_II_18	0.97	1.09	1.22	1.49	1.69	1.83	2.03	2.51	1.69	1.83	2.03	2.51	ns	
DIFF_HSTL_III_18	0.97	1.09	1.22	1.50	1.69	1.83	2.03	2.53	1.69	1.83	2.03	2.53	ns	
DIFF_SSTL3_I	1.18	1.30	1.43	1.68	1.81	1.95	2.15	2.64	1.81	1.95	2.15	2.64	ns	
DIFF_SSTL3_II	1.19	1.31	1.44	1.68	1.80	1.94	2.14	2.63	1.80	1.94	2.14	2.63	ns	
DIFF_SSTL2_I	1.02	1.14	1.27	1.57	1.80	1.94	2.14	2.62	1.80	1.94	2.14	2.62	ns	
DIFF_SSTL2_II	1.02	1.14	1.27	1.57	1.76	1.90	2.10	2.57	1.76	1.90	2.10	2.57	ns	
DIFF_SSTL18_I	0.97	1.09	1.22	1.51	1.72	1.86	2.06	2.56	1.72	1.86	2.06	2.56	ns	
DIFF_SSTL18_II	0.98	1.10	1.23	1.50	1.68	1.82	2.02	2.52	1.68	1.82	2.02	2.52	ns	
DIFF_SSTL15_II	0.94	1.06	1.19	1.46	1.67	1.81	2.01	2.50	1.67	1.81	2.01	2.50	ns	
DIFF_MOBILE_DDR	0.97	1.09	1.22	1.51	1.75	1.89	2.09	2.57	1.75	1.89	2.09	2.57	ns	

Table 29: IOB Switching Characteristics for the Automotive XA Spartan-6 and the Spartan-6Q Devices<sup>(1)</sup>

I/O Standard	T <sub>IOP1</sub>		T <sub>IOP0</sub>		T <sub>IOTP</sub>		Units	
	Speed Grade		Speed Grade		Speed Grade			
	-3	-2	-3	-2	-3	-2		
LVDS_33	1.24	1.42	1.69	1.89	3000	3000	ns	
LVDS_25	1.08	1.26	1.79	1.99	3000	3000	ns	
BLVDS_25	1.09	1.27	1.86	2.06	1.86	2.06	ns	
MINI_LVDS_33	1.25	1.43	1.71	1.91	3000	3000	ns	
MINI_LVDS_25	1.08	1.26	1.79	1.99	3000	3000	ns	
LVPECL_33	1.25	1.43	N/A	N/A	N/A	N/A	ns	
LVPECL_25	1.09	1.27	N/A	N/A	N/A	N/A	ns	
RSDS_33 (point to point)	1.24	1.42	1.71	1.91	3000	3000	ns	
RSDS_25 (point to point)	1.08	1.26	1.79	1.99	3000	3000	ns	
TMDS_33	1.29	1.47	1.68	1.88	3000	3000	ns	
PPDS_33	1.25	1.43	1.71	1.91	3000	3000	ns	
PPDS_25	1.08	1.26	1.82	2.02	3000	3000	ns	
PCI33_3	1.14	1.32	3.81	4.01	3.81	4.01	ns	
PCI66_3	1.14	1.32	3.81	4.01	3.81	4.01	ns	
DISPLAY_PORT	1.09	1.27	3.29	3.49	3.29	3.49	ns	
I2C	1.40	1.58	11.70	11.90	11.70	11.90	ns	
SMBUS	1.40	1.58	11.70	11.90	11.70	11.90	ns	
SDIO	1.43	1.61	2.78	2.98	2.78	2.98	ns	
MOBILE_DDR	1.01	1.19	2.50	2.70	2.50	2.70	ns	
HSTL_I	1.01	1.19	1.80	2.00	1.80	2.00	ns	
HSTL_II	1.01	1.19	1.86	2.06	1.86	2.06	ns	
HSTL_III	1.07	1.25	1.81	2.01	1.81	2.01	ns	
HSTL_I_18	1.05	1.23	1.91	2.11	1.91	2.11	ns	
HSTL_II_18	1.05	1.23	1.99	2.19	1.99	2.19	ns	
HSTL_III_18	1.13	1.31	1.93	2.13	1.93	2.13	ns	
SSTL3_I	1.65	1.83	1.97	2.17	1.97	2.17	ns	
SSTL3_II	1.65	1.83	2.15	2.35	2.15	2.35	ns	
SSTL2_I	1.37	1.55	1.91	2.11	1.91	2.11	ns	
SSTL2_II	1.37	1.55	2.00	2.20	2.00	2.20	ns	
SSTL18_I	0.99	1.17	1.77	1.97	1.77	1.97	ns	
SSTL18_II	1.00	1.18	1.80	2.00	1.80	2.00	ns	
SSTL15_II	1.00	1.18	1.81	2.01	1.81	2.01	ns	
DIFF_HSTL_I	1.01	1.19	1.91	2.11	1.91	2.11	ns	
DIFF_HSTL_II	1.00	1.18	1.86	2.06	1.86	2.06	ns	
DIFF_HSTL_III	1.00	1.18	1.83	2.03	1.83	2.03	ns	
DIFF_HSTL_I_18	1.04	1.22	1.93	2.13	1.93	2.13	ns	
DIFF_HSTL_II_18	1.04	1.22	1.83	2.03	1.83	2.03	ns	
DIFF_HSTL_III_18	1.04	1.22	1.83	2.03	1.83	2.03	ns	

Table 29: IOB Switching Characteristics for the Automotive XA Spartan-6 and the Spartan-6Q Devices<sup>(1)</sup> (Cont'd)

I/O Standard	T <sub>IOP1</sub>		T <sub>IOOP</sub>		T <sub>IOTP</sub>		Units	
	Speed Grade		Speed Grade		Speed Grade			
	-3	-2	-3	-2	-3	-2		
DIFF_SSTL3_I	1.26	1.44	1.95	2.15	1.95	2.15	ns	
DIFF_SSTL3_II	1.26	1.44	1.94	2.14	1.94	2.14	ns	
DIFF_SSTL2_I	1.09	1.27	1.94	2.14	1.94	2.14	ns	
DIFF_SSTL2_II	1.09	1.27	1.90	2.10	1.90	2.10	ns	
DIFF_SSTL18_I	1.04	1.22	1.86	2.06	1.86	2.06	ns	
DIFF_SSTL18_II	1.05	1.23	1.82	2.02	1.82	2.02	ns	
DIFF_SSTL15_II	1.01	1.19	1.81	2.01	1.81	2.01	ns	
DIFF_MOBILE_DDR	1.04	1.22	1.89	2.09	1.89	2.09	ns	
LVTTL, QUIETIO, 2 mA	1.42	1.60	5.64	5.84	5.64	5.84	ns	
LVTTL, QUIETIO, 4 mA	1.42	1.60	4.46	4.66	4.46	4.66	ns	
LVTTL, QUIETIO, 6 mA	1.42	1.60	3.92	4.12	3.92	4.12	ns	
LVTTL, QUIETIO, 8 mA	1.42	1.60	3.37	3.57	3.37	3.57	ns	
LVTTL, QUIETIO, 12 mA	1.42	1.60	3.42	3.62	3.42	3.62	ns	
LVTTL, QUIETIO, 16 mA	1.42	1.60	3.09	3.29	3.09	3.29	ns	
LVTTL, QUIETIO, 24 mA	1.42	1.60	2.83	3.03	2.83	3.03	ns	
LVTTL, Slow, 2 mA	1.42	1.60	4.58	4.78	4.58	4.78	ns	
LVTTL, Slow, 4 mA	1.42	1.60	3.38	3.58	3.38	3.58	ns	
LVTTL, Slow, 6 mA	1.42	1.60	2.95	3.15	2.95	3.15	ns	
LVTTL, Slow, 8 mA	1.42	1.60	2.73	2.93	2.73	2.93	ns	
LVTTL, Slow, 12 mA	1.42	1.60	2.72	2.92	2.72	2.92	ns	
LVTTL, Slow, 16 mA	1.42	1.60	2.53	2.73	2.53	2.73	ns	
LVTTL, Slow, 24 mA	1.42	1.60	2.42	2.62	2.42	2.62	ns	
LVTTL, Fast, 2 mA	1.42	1.60	4.04	4.24	4.04	4.24	ns	
LVTTL, Fast, 4 mA	1.42	1.60	2.66	2.86	2.66	2.86	ns	
LVTTL, Fast, 6 mA	1.42	1.60	2.58	2.78	2.58	2.78	ns	
LVTTL, Fast, 8 mA	1.42	1.60	2.46	2.66	2.46	2.66	ns	
LVTTL, Fast, 12 mA	1.42	1.60	1.97	2.17	1.97	2.17	ns	
LVTTL, Fast, 16 mA	1.42	1.60	1.97	2.17	1.97	2.17	ns	
LVTTL, Fast, 24 mA	1.42	1.60	1.97	2.17	1.97	2.17	ns	
LVCMOS33, QUIETIO, 2 mA	1.41	1.59	5.65	5.85	5.65	5.85	ns	
LVCMOS33, QUIETIO, 4 mA	1.41	1.59	4.20	4.40	4.20	4.40	ns	
LVCMOS33, QUIETIO, 6 mA	1.41	1.59	3.65	3.85	3.65	3.85	ns	
LVCMOS33, QUIETIO, 8 mA	1.41	1.59	3.51	3.71	3.51	3.71	ns	
LVCMOS33, QUIETIO, 12 mA	1.41	1.59	3.09	3.29	3.09	3.29	ns	
LVCMOS33, QUIETIO, 16 mA	1.41	1.59	2.91	3.11	2.91	3.11	ns	
LVCMOS33, QUIETIO, 24 mA	1.41	1.59	2.73	2.93	2.73	2.93	ns	
LVCMOS33, Slow, 2 mA	1.41	1.59	4.59	4.79	4.59	4.79	ns	
LVCMOS33, Slow, 4 mA	1.41	1.59	3.14	3.34	3.14	3.34	ns	

Table 29: IOB Switching Characteristics for the Automotive XA Spartan-6 and the Spartan-6Q Devices<sup>(1)</sup> (Cont'd)

I/O Standard	T <sub>IOP1</sub>		T <sub>IOOP</sub>		T <sub>IOTP</sub>		Units	
	Speed Grade		Speed Grade		Speed Grade			
	-3	-2	-3	-2	-3	-2		
LVCMOS33, Slow, 6 mA	1.41	1.59	2.79	2.99	2.79	2.99	ns	
LVCMOS33, Slow, 8 mA	1.41	1.59	2.79	2.99	2.79	2.99	ns	
LVCMOS33, Slow, 12 mA	1.41	1.59	2.53	2.73	2.53	2.73	ns	
LVCMOS33, Slow, 16 mA	1.41	1.59	2.45	2.65	2.45	2.65	ns	
LVCMOS33, Slow, 24 mA	1.41	1.59	2.42	2.62	2.42	2.62	ns	
LVCMOS33, Fast, 2 mA	1.41	1.59	4.05	4.25	4.05	4.25	ns	
LVCMOS33, Fast, 4 mA	1.41	1.59	2.66	2.86	2.66	2.86	ns	
LVCMOS33, Fast, 6 mA	1.41	1.59	2.46	2.66	2.46	2.66	ns	
LVCMOS33, Fast, 8 mA	1.41	1.59	2.21	2.41	2.21	2.41	ns	
LVCMOS33, Fast, 12 mA	1.41	1.59	1.80	2.00	1.80	2.00	ns	
LVCMOS33, Fast, 16 mA	1.41	1.59	1.80	2.00	1.80	2.00	ns	
LVCMOS33, Fast, 24 mA	1.41	1.59	1.80	2.00	1.80	2.00	ns	
LVCMOS25, QUIETIO, 2 mA	0.89	1.07	5.00	5.20	5.00	5.20	ns	
LVCMOS25, QUIETIO, 4 mA	0.89	1.07	3.85	4.05	3.85	4.05	ns	
LVCMOS25, QUIETIO, 6 mA	0.89	1.07	3.60	3.80	3.60	3.80	ns	
LVCMOS25, QUIETIO, 8 mA	0.89	1.07	3.34	3.54	3.34	3.54	ns	
LVCMOS25, QUIETIO, 12 mA	0.89	1.07	2.98	3.18	2.98	3.18	ns	
LVCMOS25, QUIETIO, 16 mA	0.89	1.07	2.79	2.99	2.79	2.99	ns	
LVCMOS25, QUIETIO, 24 mA	0.89	1.07	2.64	2.84	2.64	2.84	ns	
LVCMOS25, Slow, 2 mA	0.89	1.07	3.96	4.16	3.96	4.16	ns	
LVCMOS25, Slow, 4 mA	0.89	1.07	2.96	3.16	2.96	3.16	ns	
LVCMOS25, Slow, 6 mA	0.89	1.07	2.88	3.08	2.88	3.08	ns	
LVCMOS25, Slow, 8 mA	0.89	1.07	2.63	2.83	2.63	2.83	ns	
LVCMOS25, Slow, 12 mA	0.89	1.07	2.15	2.35	2.15	2.35	ns	
LVCMOS25, Slow, 16 mA	0.89	1.07	2.15	2.35	2.15	2.35	ns	
LVCMOS25, Slow, 24 mA	0.89	1.07	2.15	2.35	2.15	2.35	ns	
LVCMOS25, Fast, 2 mA	0.89	1.07	3.52	3.72	3.52	3.72	ns	
LVCMOS25, Fast, 4 mA	0.89	1.07	2.43	2.63	2.43	2.63	ns	
LVCMOS25, Fast, 6 mA	0.89	1.07	2.23	2.43	2.23	2.43	ns	
LVCMOS25, Fast, 8 mA	0.89	1.07	2.16	2.36	2.16	2.36	ns	
LVCMOS25, Fast, 12 mA	0.89	1.07	1.70	1.90	1.70	1.90	ns	
LVCMOS25, Fast, 16 mA	0.89	1.07	1.70	1.90	1.70	1.90	ns	
LVCMOS25, Fast, 24 mA	0.89	1.07	1.70	1.90	1.70	1.90	ns	
LVCMOS18, QUIETIO, 2 mA	1.25	1.43	6.11	6.31	6.11	6.31	ns	
LVCMOS18, QUIETIO, 4 mA	1.25	1.43	4.88	5.08	4.88	5.08	ns	
LVCMOS18, QUIETIO, 6 mA	1.25	1.43	4.20	4.40	4.20	4.40	ns	
LVCMOS18, QUIETIO, 8 mA	1.25	1.43	3.86	4.06	3.86	4.06	ns	
LVCMOS18, QUIETIO, 12 mA	1.25	1.43	3.49	3.69	3.49	3.69	ns	

Table 34: SSO Limit per V<sub>CCO</sub>/GND Pair (Cont'd)

V <sub>CCO</sub>	I/O Standard	Drive	Slew	SSO Limit per V <sub>CCO</sub> /GND Pair			
				All TQG144, CPG196, CSG225, FT(G)256, and LX devices in CSG324		All CS(G)484, FG(G)484, FG(G)676, FG(G)900, and LXT devices in CSG324	
				Bank 0/2	Bank 1/3	Bank 0/2	Bank 1/3/4/5
3.3V	LVCMOS33	2	Fast	42	46	42	44
			Slow	50	55	50	49
			QuietIO	60	68	60	60
		4	Fast	21	27	21	25
			Slow	32	37	32	32
			QuietIO	39	42	39	37
		6	Fast	14	19	14	17
			Slow	19	25	19	22
			QuietIO	29	30	29	25
		8	Fast	11	15	11	14
			Slow	15	20	15	18
			QuietIO	25	24	25	20
		12	Fast	1	3	1	1
			Slow	2	5	2	2
			QuietIO	4	9	4	7
		16	Fast	1	2	1	1
			Slow	1	5	1	1
			QuietIO	3	10	3	8
		24	Fast	1	2	1	1
			Slow	2	5	2	1
			QuietIO	7	9	7	7

## Input Serializer/Deserializer Switching Characteristics

Table 37: ISERDES2 Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
<b>Setup/Hold for Control Lines</b>						
T <sub>ISCKC_BITSLIP</sub> / T <sub>ISCKC_BITSLIP</sub>	BITSLIP pin Setup/Hold with respect to CLKDIV	0.16/ -0.09	0.20/ -0.09	0.31/ -0.09	0.34/ -0.14	ns
T <sub>ISCKC_CE</sub> / T <sub>ISCKC_CE</sub>	CE pin Setup/Hold with respect to CLK	0.71/ -0.47	0.71/ -0.42	0.97/ -0.42	1.39/ -0.71	ns
<b>Setup/Hold for Data Lines</b>						
T <sub>ISDCK_D</sub> / T <sub>ISCKD_D</sub>	D pin Setup/Hold with respect to CLK	0.24/ -0.15	0.25/ -0.05	0.29/ -0.05	0.09/ -0.05	ns
T <sub>ISDCK_DDLY</sub> / T <sub>ISCKD_DDLY</sub>	DDLY pin Setup/Hold with respect to CLK (using IODELAY2)	-0.25/ 0.30	-0.25/ 0.42	-0.25/ 0.56	-0.54/ 0.67	ns
T <sub>ISDCK_D_DDR</sub> / T <sub>ISCKD_D_DDR</sub>	D pin Setup/Hold with respect to CLK at DDR mode	-0.03/ 0.04	-0.03/ 0.16	-0.03/ 0.18	-0.05/ 0.12	ns
T <sub>ISDCK_DDLY_DDR</sub> / T <sub>ISCKD_DDLY_DDR</sub>	D pin Setup/Hold with respect to CLK at DDR mode (using IODELAY2)	-0.40/ 0.48	-0.40/ 0.53	-0.40/ 0.71	-0.71/ 0.86	ns
<b>Sequential Delays</b>						
T <sub>ISCKO_Q</sub>	CLKDIV to out at Q pin	1.30	1.44	2.02	2.22	ns
F <sub>CLKDIV</sub>	CLKDIV maximum frequency	270	262.5	250	125	MHz

## Output Serializer/Deserializer Switching Characteristics

Table 38: OSERDES2 Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
<b>Setup/Hold</b>						
T <sub>OSDCK_D</sub> / T <sub>OSCKD_D</sub>	D input Setup/Hold with respect to CLKDIV	-0.03/ 1.02	-0.03/ 1.17	-0.03/ 1.27	-0.02/ 0.23	ns
T <sub>OSDCK_T</sub> / T <sub>OSCKD_T</sub> <sup>(1)</sup>	T input Setup/Hold with respect to CLK	-0.05/ 1.03	-0.05/ 1.13	-0.05/ 1.23	-0.05/ 0.24	ns
T <sub>OSCCK_OCE</sub> / T <sub>OSCKC_OCE</sub>	OCE input Setup/Hold with respect to CLK	0.12/ -0.03	0.15/ -0.03	0.24/ -0.03	0.28/ -0.17	ns
T <sub>OSCCK_TCE</sub> / T <sub>OSCKC_TCE</sub>	TCE input Setup/Hold with respect to CLK	0.14/ -0.08	0.17/ -0.08	0.27/ -0.08	0.31/ -0.16	ns
<b>Sequential Delays</b>						
T <sub>OSCKO_OQ</sub>	Clock to out from CLK to OQ	0.94	1.11	1.51	1.89	ns
T <sub>OSCKO_TQ</sub>	Clock to out from CLK to TQ	0.94	1.11	1.51	1.91	ns
F <sub>CLKDIV</sub>	CLKDIV maximum frequency	270	262.5	250	125	MHz

**Notes:**

1. T<sub>OSDCK\_T2</sub> / T<sub>OSCKD\_T2</sub> (T input setup/hold with respect to CLKDIV) are reported as T<sub>OSDCK\_T</sub> / T<sub>OSCKD\_T</sub> in TRACE report.

## Block RAM Switching Characteristics

Table 43: Block RAM Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
<b>Block RAM Clock to Out Delays</b>						
T <sub>RCKO_DO</sub>	Clock CLK to DOUT output (without output register) <sup>(1)</sup>	1.85	2.10	2.10	3.50	ns, Max
T <sub>RCKO_DO_REG</sub>	Clock CLK to DOUT output (with output register) <sup>(2)</sup>	1.60	1.75	1.75	2.30	ns, Max
<b>Setup and Hold Times Before/After Clock CLK</b>						
T <sub>RCKC_ADDR</sub> /T <sub>RCKC_ADDR</sub>	ADDR inputs for XC devices <sup>(3)</sup>	0.35/ 0.10	0.40/ 0.12	0.40/ 0.12	0.50/ 0.15	ns, Min
	ADDR inputs for XA and XQ devices <sup>(3)</sup>	0.35/ 0.17	N/A	0.40/ 0.17	0.50/ 0.15	ns, Min
T <sub>RDCK_DI</sub> /T <sub>RCKD_DI</sub>	DIN inputs <sup>(4)</sup>	0.30/ 0.10	0.30/ 0.10	0.30/ 0.10	0.40/ 0.15	ns, Min
T <sub>RCKC_EN</sub> /T <sub>RCKC_EN</sub>	Block RAM Enable (EN) input	0.22/ 0.05	0.25/ 0.06	0.25/ 0.06	0.44/ 0.10	ns, Min
T <sub>RCKC_REGCE</sub> /T <sub>RCKC_REGCE</sub>	CE input of output register	0.20/ 0.10	0.20/ 0.10	0.20/ 0.10	0.28/ 0.15	ns, Min
T <sub>RCKC_WE</sub> /T <sub>RCKC_WE</sub>	Write Enable (WE) input	0.25/ 0.10	0.33/ 0.10	0.33/ 0.10	0.28/ 0.15	ns, Min
<b>Maximum Frequency</b>						
F <sub>MAX</sub>	Block RAM in all modes	320	280	280	150	MHz

**Notes:**

1. T<sub>RCKO\_DO</sub> includes T<sub>RCKO\_DOA</sub> and T<sub>RCKO\_DOPA</sub> as well as the B port equivalent timing parameters.
2. T<sub>RCKO\_DO\_REG</sub> includes T<sub>RCKO\_DOA\_REG</sub> and T<sub>RCKO\_DOPA\_REG</sub> as well as the B port equivalent timing parameters.
3. The ADDR setup and hold must be met when EN is asserted (even when WE is deasserted). Otherwise, block RAM data corruption is possible.
4. T<sub>RDCK\_DI</sub> includes both A and B inputs as well as the parity inputs of A and B.

## DCM Switching Characteristics

Table 53: Operating Frequency Ranges and Conditions for the Delay-Locked Loop (DLL)<sup>(1)</sup>

Symbol	Description	Speed Grade								Units	
		-3		-3N		-2		-1L			
		Min	Max	Min	Max	Min	Max	Min	Max		
<b>Input Frequency Ranges</b>											
CLKIN_FREQ_DLL	Frequency of the CLKIN clock input when the CLKDV output is not used.	5 <sup>(2)</sup>	280 <sup>(3)</sup>	5 <sup>(2)</sup>	280 <sup>(3)</sup>	5 <sup>(2)</sup>	250 <sup>(3)</sup>	5 <sup>(2)</sup>	175 <sup>(3)</sup>	MHz	
	Frequency of the CLKIN clock input when using the CLKDV output.	5 <sup>(2)</sup>	280 <sup>(3)</sup>	5 <sup>(2)</sup>	280 <sup>(3)</sup>	5 <sup>(2)</sup>	250 <sup>(3)</sup>	5 <sup>(2)</sup>	133 <sup>(3)</sup>	MHz	
<b>Input Pulse Requirements</b>											
CLKIN_PULSE	CLKIN pulse width as a percentage of the CLKIN period for CLKIN_FREQ_DLL < 150 MHz	40	60	40	60	40	60	40	60	%	
	CLKIN pulse width as a percentage of the CLKIN period for CLKIN_FREQ_DLL > 150 MHz	45	55	45	55	45	55	45	55	%	
<b>Input Clock Jitter Tolerance and Delay Path Variation<sup>(4)</sup></b>											
CLKIN_CYC_JITT_DLL_LF	Cycle-to-cycle jitter at the CLKIN input for CLKIN_FREQ_DLL < 150 MHz	–	±300	–	±300	–	±300	–	±300	ps	
CLKIN_CYC_JITT_DLL_HF	Cycle-to-cycle jitter at the CLKIN input for CLKIN_FREQ_DLL > 150 MHz.	–	±150	–	±150	–	±150	–	±150	ps	
CLKIN_PER_JITT_DLL	Period jitter at the CLKIN input.	–	±1	–	±1	–	±1	–	±1	ns	
CLKFB_DELAY_VAR_EXT	Allowable variation of the off-chip feedback delay from the DCM output to the CLKFB input.	–	±1	–	±1	–	±1	–	±1	ns	

### Notes:

1. DLL specifications apply when using any of the DLL outputs: CLK0, CLK90, CLK180, CLK270, CLK2X, CLK2X180, or CLKDV.
2. When operating independently of the DLL, the DFS supports lower CLKIN\_FREQ\_DLL frequencies. See Table 55.
3. The CLKIN\_DIVIDE\_BY\_2 attribute increases the effective input frequency range. When set to TRUE, the input clock frequency is divided by two as it enters the DCM. Input clock frequencies for the clock buffer being used can be increased up to the F<sub>MAX</sub> (see Table 48 and Table 49 for BUFG and BUFIO2 limits). When used with CLK\_FEEDBACK=2X, the input clock frequency matches the frequency for CLK2X, and is limited to CLKOUT\_FREQ\_2X.
4. CLKIN\_FREQ\_DLL input jitter beyond these limits can cause the DCM to lose LOCK, indicated by the LOCKED output deasserting. The user must then reset the DCM.
5. When using both DCMs in a CMT, both DCMs must be LOCKED.

Table 54: Switching Characteristics for the Delay-Locked Loop (DLL)<sup>(1)</sup> (Cont'd)

Symbol	Description	Speed Grade								Units	
		-3		-3N		-2		-1L			
		Min	Max	Min	Max	Min	Max	Min	Max		
LOCK_DLL <sup>(3)</sup>	When using the DLL alone: The time from deassertion at the DCM's reset input to the rising transition at its LOCKED output. When the DCM is locked, the CLKIN and CLKFB signals are in phase. CLKIN_FREQ_DLL < 50 MHz.	—	5	—	5	—	5	—	5	ms	
	When using the DLL alone: The time from deassertion at the DCM's reset input to the rising transition at its LOCKED output. When the DCM is locked, the CLKIN and CLKFB signals are in phase. CLKIN_FREQ_DLL > 50 MHz.	—	0.60	—	0.60	—	0.60	—	0.60	ms	
<b>Delay Lines</b>											
DCM_DELAY_STEP <sup>(5)</sup>	Finest delay resolution, averaged over all steps.	10	40	10	40	10	40	10	40	ps	

**Notes:**

- The values in this table are based on the operating conditions described in Table 2 and Table 53.
- Indicates the maximum amount of output jitter that the DCM adds to the jitter on the CLKIN input.
- For optimal jitter tolerance and faster LOCK time, use the CLKIN\_PERIOD attribute.
- Some jitter and duty-cycle specifications include 1% of input clock period or 0.01 UI. For example, this data sheet specifies a maximum jitter of  $\pm(1\% \text{ of CLKIN period} + 150 \text{ ps})$ . Assuming that the CLKIN frequency is 100 MHz, the equivalent CLKIN period is 10 ns. Since 1% of 10 ns is 0.1 ns or 100 ps, the maximum jitter is  $\pm(100 \text{ ps} + 150 \text{ ps}) = \pm250 \text{ ps}$ .
- A typical delay step size is 23 ps.
- The timing analysis tools use the CLK\_FEEDBACK = 1X condition for the CLKIN\_CLKFB\_PHASE value (reported as phase error). When using CLK\_FEEDBACK = 2X, add 100 ps to the phase error for the CLKIN\_CLKFB\_PHASE value (as shown in this table).

Table 55: Recommended Operating Conditions for the Digital Frequency Synthesizer (DFS)<sup>(1)</sup>

Symbol	Description	Speed Grade								Units	
		-3		-3N		-2		-1L			
		Min	Max	Min	Max	Min	Max	Min	Max		
<b>Input Frequency Ranges<sup>(2)</sup></b>											
CLKIN_FREQ_FX	Frequency for the CLKIN input. Also described as F <sub>CLKIN</sub> .	0.5	375 <sup>(3)</sup>	0.5	375 <sup>(3)</sup>	0.5	333 <sup>(3)</sup>	0.5	200 <sup>(3)</sup>	MHz	
<b>Input Clock Jitter Tolerance<sup>(4)</sup></b>											
CLKIN_CYC_JITT_FX_LF	Cycle-to-cycle jitter at the CLKIN input, based on CLKFX output frequency: F <sub>CLKFX</sub> < 150 MHz.	—	$\pm 300$	—	$\pm 300$	—	$\pm 300$	—	$\pm 300$	ps	
CLKIN_CYC_JITT_FX_HF	Cycle-to-cycle jitter at the CLKIN input, based on CLKFX output frequency: F <sub>CLKFX</sub> > 150 MHz.	—	$\pm 150$	—	$\pm 150$	—	$\pm 150$	—	$\pm 150$	ps	
CLKIN_PER_JITT_FX	Period jitter at the CLKIN input.	—	$\pm 1$	—	$\pm 1$	—	$\pm 1$	—	$\pm 1$	ns	

**Notes:**

- DFS specifications apply when using either of the DFS outputs (CLKFX or CLKFX180).
- When using both DFS and DLL outputs on the same DCM, follow the more restrictive CLKIN\_FREQ\_DLL specifications in Table 53.
- The CLKIN\_DIVIDE\_BY\_2 attribute increases the effective input frequency range. When set to TRUE, the input clock frequency is divided by two as it enters the DCM. Input clock frequencies for the clock buffer being used can be increased up to the F<sub>MAX</sub> (see Table 48 and Table 49 for BUFG and BUFI02 limits).
- CLKIN input jitter beyond these limits can cause the DCM to lose LOCK.

Table 56: Switching Characteristics for the Digital Frequency Synthesizer (DFS) for DCM\_SP<sup>(1)</sup>

Symbol	Description	Speed Grade								Units	
		-3		-3N		-2		-1L			
		Min	Max	Min	Max	Min	Max	Min	Max		
<b>Output Frequency Ranges</b>											
CLKOUT_FREQ_FX	Frequency for the CLKFX and CLKFX180 outputs	5	375	5	375	5	333	5	200	MHz	
<b>Output Clock Jitter<sup>(2)(3)</sup></b>											
CLKOUT_PER_JITT_FX	Period jitter at the CLKFX and CLKFX180 outputs. When CLKIN < 20 MHz	Use the Clocking Wizard								ps	
	Period jitter at the CLKFX and CLKFX180 outputs. When CLKIN > 20 MHz	Typical = ±(1% of CLKFX period + 100)								ps	
<b>Duty Cycle<sup>(4)(5)</sup></b>											
CLKOUT_DUTY_CYCLE_FX	Duty cycle precision for the CLKFX and CLKFX180 outputs including the BUFGMUX and clock tree duty-cycle distortion	Maximum = ±(1% of CLKFX period + 350)								ps	
<b>Phase Alignment<sup>(5)</sup></b>											
CLKOUT_PHASE_FX	Phase offset between the DFS CLKFX output and the DLL CLK0 output when both the DFS and DLL are used	–	±200	–	±200	–	±200	–	±250	ps	
CLKOUT_PHASE_FX180	Phase offset between the DFS CLKFX180 output and the DLL CLK0 output when both the DFS and DLL are used	Maximum = ±(1% of CLKFX period + 200)								ps	
<b>LOCKED Time</b>											
LOCK_FX <sup>(2)</sup>	When FCLKIN < 50 MHz, the time from deassertion at the DCM's reset input to the rising transition at its LOCKED output. The DFS asserts LOCKED when the CLKFX and CLKFX180 signals are valid. When using both the DLL and the DFS, use the longer locking time.	–	5	–	5	–	5	–	5	ms	
	When FCLKIN > 50 MHz, the time from deassertion at the DCM's reset input to the rising transition at its LOCKED output. The DFS asserts LOCKED when the CLKFX and CLKFX180 signals are valid. When using both the DLL and the DFS, use the longer locking time.	–	0.45	–	0.45	–	0.45	–	0.60	ms	

**Notes:**

- The values in this table are based on the operating conditions described in Table 2 and Table 55.
- For optimal jitter tolerance and a faster LOCK time, use the CLKIN\_PERIOD attribute.
- Output jitter is characterized with no input jitter. Output jitter strongly depends on the environment, including the number of SSOs, the output drive strength, CLB utilization, CLB switching activities, switching frequency, power supply, and PCB design. The actual maximum output jitter depends on the system application.
- The CLKFX, CLKFXDV, and CLKFX180 outputs have a duty cycle of approximately 50%.
- Some duty cycle and alignment specifications include a percentage of the CLKFX output period. For example, this data sheet specifies a maximum CLKFX jitter of ±(1% of CLKFX period + 200 ps). Assuming that the CLKFX output frequency is 100 MHz, the equivalent CLKFX period is 10 ns, and 1% of 10 ns is 0.1 ns or 100 ps. Accordingly, the maximum jitter is ±(100 ps + 200 ps) = ±300 ps.

Table 59: Switching Characteristics for the Phase-Shift Clock in Variable Phase Mode<sup>(1)</sup>

Symbol	Description	Amount of Phase Shift	Units
<b>Phase Shifting Range</b>			
MAX_STEPS <sup>(2)</sup>	When CLKIN < 60 MHz, the maximum allowed number of DCM_DELAY_STEP steps for a given CLKIN clock period, where T = CLKIN clock period in ns. When using CLKIN_DIVIDE_BY_2 = TRUE, double the clock-effective clock period.	$\pm(\text{INTEGER}(10 \times (\text{CLKIN} - 3 \text{ ns})))$	steps
	When CLKIN $\geq$ 60 MHz, the maximum allowed number of DCM_DELAY_STEP steps for a given CLKIN clock period, where T = CLKIN clock period in ns. When using CLKIN_DIVIDE_BY_2 = TRUE, double the clock-effective clock period.	$\pm(\text{INTEGER}(15 \times (\text{CLKIN} - 3 \text{ ns})))$	steps
FINE_SHIFT_RANGE_MIN	Minimum guaranteed delay for variable phase shifting.	$\pm(\text{MAX_STEPS} \times \text{DCM_DELAY_STEP_MIN})$	ps
FINE_SHIFT_RANGE_MAX	Maximum guaranteed delay for variable phase shifting	$\pm(\text{MAX_STEPS} \times \text{DCM_DELAY_STEP_MAX})$	ps

**Notes:**

- The values in this table are based on the operating conditions described in Table 53 and Table 58.
- The maximum variable phase shift range, MAX\_STEPS, is only valid when the DCM has no initial fixed-phase shifting, that is, the PHASE\_SHIFT attribute is set to 0.
- The DCM\_DELAY\_STEP values are provided at the end of Table 54.

Table 60: Miscellaneous DCM Timing Parameters<sup>(1)</sup>

Symbol	Description	Min	Max	Units
DCM_RST_PW_MIN	Minimum duration of a RST pulse width	3	–	CLKIN cycles

**Notes:**

- This limit only applies to applications that use the DCM DLL outputs (CLK0, CLK90, CLK180, CLK270, CLK2X, CLK2X180, and CLKDV). The DCM DFS outputs (CLKFX, CLKFXDV, CLKFX180) are unaffected.

Table 61: Frequency Synthesis

Attribute	Min	Max
CLKFX_MULTIPLY (DCM_SP)	2	32
CLKFX_DIVIDE (DCM_SP)	1	32
CLKDV_DIVIDE (DCM_SP)	1.5	16
CLKFX_MULTIPLY (DCM_CLKGEN)	2	256
CLKFX_DIVIDE (DCM_CLKGEN)	1	256
CLKFXDV_DIVIDE (DCM_CLKGEN)	2	32

Table 62: DCM Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
T <sub>DMCCK_PSEN</sub> /T <sub>DMCKC_PSEN</sub>	PSEN Setup/Hold	1.50/ 0.00	1.50/ 0.00	1.50/ 0.00	1.50/ 0.00	ns
T <sub>DMCCK_PSINCDEC</sub> /T <sub>DMCKC_PSINCDEC</sub>	PSINCDEC Setup/Hold	1.50/ 0.00	1.50/ 0.00	1.50/ 0.00	1.50/ 0.00	ns
T <sub>DMCKO_PSDONE</sub>	Clock to out of PSDONE	1.50	1.50	1.50	1.50	ns

Table 64: Global Clock Input to Output Delay With DCM in System-Synchronous Mode

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
LVCMOS25 Global Clock Input to Output Delay using Output Flip-Flop, 12mA, Fast Slew Rate, <i>with</i> DCM in System-Synchronous Mode.							
TICKOFDCM	Global Clock and OUTFF <i>with</i> DCM	XC6SLX4	4.23	N/A	6.11	6.60	ns
		XC6SLX9	4.23	5.17	6.11	6.60	ns
		XC6SLX16	4.28	4.57	5.34	6.36	ns
		XC6SLX25	3.95	4.18	4.59	6.91	ns
		XC6SLX25T	3.95	4.18	4.59	N/A	ns
		XC6SLX45	4.37	4.70	5.50	6.85	ns
		XC6SLX45T	4.37	4.70	5.50	N/A	ns
		XC6SLX75	3.90	4.23	4.77	6.31	ns
		XC6SLX75T	3.90	4.23	4.77	N/A	ns
		XC6SLX100	3.86	4.16	4.66	7.25	ns
		XC6SLX100T	3.90	4.16	4.66	N/A	ns
		XC6SLX150	4.03	4.33	4.83	6.63	ns
		XC6SLX150T	4.03	4.33	4.83	N/A	ns
		XA6SLX4	4.55	N/A	6.11	N/A	ns
		XA6SLX9	4.55	N/A	6.11	N/A	ns
		XA6SLX16	4.62	N/A	5.33	N/A	ns
		XA6SLX25	4.27	N/A	4.59	N/A	ns
		XA6SLX25T	4.27	N/A	4.69	N/A	ns
		XA6SLX45	4.69	N/A	5.50	N/A	ns
		XA6SLX45T	4.69	N/A	5.50	N/A	ns
		XA6SLX75	4.22	N/A	4.77	N/A	ns
		XA6SLX75T	4.22	N/A	4.77	N/A	ns
		XA6SLX100	N/A	N/A	5.34	N/A	ns
		XQ6SLX75	N/A	N/A	4.77	6.31	ns
		XQ6SLX75T	4.22	N/A	4.77	N/A	ns
		XQ6SLX150	N/A	N/A	4.96	6.63	ns
		XQ6SLX150T	4.62	N/A	4.96	N/A	ns

**Notes:**

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. DCM output jitter is already included in the timing calculation.

Table 73: Global Clock Setup and Hold With DCM in Source-Synchronous Mode

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
<b>Input Setup and Hold Time Relative to Global Clock Input Signal for LVCMOS25 Standard.<sup>(1)</sup></b>							
T <sub>PSDCM0</sub> / T <sub>PHDCM0</sub>	No Delay Global Clock and IFF <sup>(2)</sup> with DCM in Source-Synchronous Mode	XC6SLX4	0.71/0.65	N/A	0.72/1.22	1.58/1.18	ns
		XC6SLX9	0.71/0.69	0.71/1.19	0.72/1.36	1.58/1.18	ns
		XC6SLX16	0.86/0.52	0.92/0.57	1.04/0.60	1.02/1.06	ns
		XC6SLX25	0.84/0.58	0.90/0.59	1.01/0.59	1.58/1.07	ns
		XC6SLX25T	0.84/0.58	0.90/0.59	1.01/0.59	N/A	ns
		XC6SLX45	0.85/0.70	0.90/0.76	0.98/0.79	1.34/1.34	ns
		XC6SLX45T	0.85/0.70	0.90/0.76	0.98/0.79	N/A	ns
		XC6SLX75	1.00/0.62	1.06/0.63	1.15/0.63	1.65/1.46	ns
		XC6SLX75T	1.00/0.71	1.06/0.72	1.15/0.72	N/A	ns
		XC6SLX100	0.81/0.68	0.81/0.69	0.94/0.69	1.42/2.07	ns
		XC6SLX100T	0.81/0.68	0.81/0.69	0.94/0.69	N/A	ns
		XC6SLX150	0.68/0.98	0.69/0.99	0.79/0.99	1.45/1.60	ns
		XC6SLX150T	0.68/0.98	0.69/0.99	0.79/0.99	N/A	ns
		XA6SLX4	0.81/0.74	N/A	0.72/1.36	N/A	ns
		XA6SLX9	0.81/0.74	N/A	0.72/1.36	N/A	ns
		XA6SLX16	1.01/0.56	N/A	1.04/0.60	N/A	ns
		XA6SLX25	0.94/0.76	N/A	1.06/0.77	N/A	ns
		XA6SLX25T	0.94/0.76	N/A	1.14/0.77	N/A	ns
		XA6SLX45	0.86/0.74	N/A	0.98/0.78	N/A	ns
		XA6SLX45T	0.86/0.74	N/A	0.98/0.78	N/A	ns
		XA6SLX75	1.02/0.71	N/A	1.15/0.72	N/A	ns
		XA6SLX75T	1.02/0.71	N/A	1.15/0.72	N/A	ns
		XA6SLX100	N/A	N/A	1.37/0.75	N/A	ns
		XQ6SLX75	N/A	N/A	1.15/0.72	1.65/1.46	ns
		XQ6SLX75T	1.02/0.71	N/A	1.15/0.72	N/A	ns
		XQ6SLX150	N/A	N/A	0.79/1.15	1.45/1.60	ns
		XQ6SLX150T	0.73/1.15	N/A	0.79/1.15	N/A	ns

**Notes:**

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage. These measurements include DCM CLK0 jitter.
2. IFF = Input Flip-Flop or Latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 74: Global Clock Setup and Hold With PLL in System-Synchronous Mode

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
<b>Input Setup and Hold Time Relative to Global Clock Input Signal for LVCMOS25 Standard.<sup>(1)</sup></b>							
T <sub>PSPLL</sub> / T <sub>PHPLL</sub>	No Delay Global Clock and IFF <sup>(2)</sup> with PLL in System-Synchronous Mode	XC6SLX4	1.37/0.25	N/A	1.52/0.41	2.07/0.69	ns
		XC6SLX9	1.37/0.21	1.48/0.21	1.52/0.26	2.07/0.69	ns
		XC6SLX16	1.33/-0.03	1.53/-0.02	1.60/-0.02	1.57/0.48	ns
		XC6SLX25	1.65/0.28	1.71/0.28	1.91/0.28	2.44/0.76	ns
		XC6SLX25T	1.65/0.28	1.71/0.28	1.91/0.28	N/A	ns
		XC6SLX45	1.55/0.18	1.64/0.18	1.75/0.18	2.02/0.90	ns
		XC6SLX45T	1.55/0.18	1.64/0.18	1.75/0.18	N/A	ns
		XC6SLX75	1.77/0.21	1.89/0.21	2.13/0.21	2.46/0.53	ns
		XC6SLX75T	1.77/0.21	1.89/0.21	2.13/0.21	N/A	ns
		XC6SLX100	1.44/0.32	1.52/0.32	1.70/0.32	1.78/0.86	ns
		XC6SLX100T	1.44/0.32	1.52/0.32	1.70/0.32	N/A	ns
		XC6SLX150	1.39/0.49	1.48/0.49	1.67/0.49	1.94/0.94	ns
		XC6SLX150T	1.39/0.49	1.48/0.49	1.67/0.49	N/A	ns
		XA6SLX4	1.61/0.10	N/A	1.64/0.28	N/A	ns
		XA6SLX9	1.61/0.10	N/A	1.64/0.28	N/A	ns
		XA6SLX16	1.89/-0.08	N/A	1.72/-0.08	N/A	ns
		XA6SLX25	1.85/0.16	N/A	2.08/0.16	N/A	ns
		XA6SLX25T	1.85/0.16	N/A	2.17/0.16	N/A	ns
		XA6SLX45	1.58/0.07	N/A	1.87/0.03	N/A	ns
		XA6SLX45T	1.58/0.07	N/A	1.87/0.03	N/A	ns
		XA6SLX75	1.80/0.06	N/A	2.25/0.06	N/A	ns
		XA6SLX75T	1.80/0.06	N/A	2.25/0.06	N/A	ns
		XA6SLX100	N/A	N/A	2.34/0.14	N/A	ns
		XQ6SLX75	N/A	N/A	2.25/0.06	2.46/0.53	ns
		XQ6SLX75T	1.80/0.06	N/A	2.25/0.06	N/A	ns
		XQ6SLX150	N/A	N/A	1.79/0.37	1.94/0.94	ns
		XQ6SLX150T	1.43/0.37	N/A	1.79/0.37	N/A	ns

**Notes:**

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage. These measurements include PLL CLKOUT0 jitter.
2. IFF = Input Flip-Flop or Latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 75: Global Clock Setup and Hold With PLL in Source-Synchronous Mode

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
<b>Input Setup and Hold Time Relative to Global Clock Input Signal for LVCMOS25 Standard.<sup>(1)</sup></b>							
T <sub>PSPLL0</sub> / T <sub>PHPPLL0</sub>	No Delay Global Clock and IFF <sup>(2)</sup> with PLL in Source-Synchronous Mode	XC6SLX4	0.47/1.08	N/A	0.47/1.60	1.15/1.68	ns
		XC6SLX9	0.47/1.08	0.47/1.35	0.47/1.60	1.15/1.68	ns
		XC6SLX16	0.37/0.75	0.37/0.82	0.51/0.94	0.57/1.31	ns
		XC6SLX25	0.69/1.06	0.69/1.06	0.69/1.06	1.86/1.67	ns
		XC6SLX25T	0.69/1.06	0.69/1.06	0.69/1.06	N/A	ns
		XC6SLX45	0.57/1.05	0.65/1.10	0.65/1.18	1.02/1.65	ns
		XC6SLX45T	0.57/1.06	0.65/1.10	0.65/1.18	N/A	ns
		XC6SLX75	0.86/1.04	0.87/1.04	0.90/1.04	1.34/1.55	ns
		XC6SLX75T	0.86/1.04	0.87/1.04	0.90/1.04	N/A	ns
		XC6SLX100	0.53/1.13	0.54/1.13	0.55/1.13	0.89/2.39	ns
		XC6SLX100T	0.53/1.13	0.54/1.13	0.55/1.13	N/A	ns
		XC6SLX150	0.50/1.31	0.51/1.31	0.52/1.31	1.02/1.72	ns
		XC6SLX150T	0.50/1.31	0.51/1.31	0.52/1.31	N/A	ns
		XA6SLX4	0.71/0.93	N/A	0.62/1.47	N/A	ns
		XA6SLX9	0.71/0.93	N/A	0.62/1.47	N/A	ns
		XA6SLX16	0.92/0.69	N/A	0.63/0.82	N/A	ns
		XA6SLX25	0.99/0.94	N/A	0.96/0.94	N/A	ns
		XA6SLX25T	0.99/0.94	N/A	1.04/0.94	N/A	ns
		XA6SLX45	0.63/1.02	N/A	0.72/1.05	N/A	ns
		XA6SLX45T	0.63/1.02	N/A	0.72/1.05	N/A	ns
		XA6SLX75	0.88/0.89	N/A	1.02/0.89	N/A	ns
		XA6SLX75T	0.88/0.89	N/A	1.02/0.89	N/A	ns
		XA6SLX100	N/A	N/A	1.25/0.96	N/A	ns
		XQ6SLX75	N/A	N/A	1.02/0.89	1.34/1.55	ns
		XQ6SLX75T	0.88/0.89	N/A	1.02/0.89	N/A	ns
		XQ6SLX150	N/A	N/A	0.63/1.19	1.02/1.72	ns
		XQ6SLX150T	0.60/1.19	N/A	0.63/1.19	N/A	ns

**Notes:**

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage. These measurements include PLL CLKOUT0 jitter.
2. IFF = Input Flip-Flop or Latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 76: Global Clock Setup and Hold With DCM and PLL in System-Synchronous Mode

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
<b>Input Setup and Hold Time Relative to Global Clock Input Signal for LVCMOS25 Standard.<sup>(1)</sup></b>							
$T_{PSDCMPLL}$ / $T_{PHDCMPLL}$	No Delay Global Clock and IFF <sup>(2)</sup> with DCM in System-Synchronous Mode and PLL in DCM2PLL Mode.	XC6SLX4	1.16/0.49	N/A	1.39/0.49	2.36/0.59	ns
		XC6SLX9	1.16/0.44	1.37/0.44	1.39/0.44	2.36/0.59	ns
		XC6SLX16	1.44/-0.08	1.49/-0.04	1.62/-0.04	2.06/0.55	ns
		XC6SLX25	1.52/0.42	1.65/0.42	1.83/0.42	2.52/0.43	ns
		XC6SLX25T	1.52/0.42	1.65/0.42	1.83/0.42	N/A	ns
		XC6SLX45	1.54/0.39	1.59/0.39	1.75/0.39	2.48/0.76	ns
		XC6SLX45T	1.54/0.39	1.59/0.39	1.75/0.39	N/A	ns
		XC6SLX75	1.72/0.41	1.80/0.41	1.99/0.41	2.60/0.75	ns
		XC6SLX75T	1.72/0.41	1.80/0.41	1.99/0.41	N/A	ns
		XC6SLX100	1.34/0.51	1.46/0.51	1.64/0.51	2.12/0.90	ns
		XC6SLX100T	1.34/0.51	1.46/0.51	1.64/0.51	N/A	ns
		XC6SLX150	1.30/0.60	1.40/0.60	1.55/0.60	2.57/0.97	ns
		XC6SLX150T	1.30/0.60	1.40/0.60	1.55/0.60	N/A	ns
		XA6SLX4	1.58/0.37	N/A	1.58/0.37	N/A	ns
		XA6SLX9	1.58/0.37	N/A	1.58/0.37	N/A	ns
		XA6SLX16	2.67/0.35	N/A	2.67/0.17	N/A	ns
		XA6SLX25	1.74/0.27	N/A	1.95/0.27	N/A	ns
		XA6SLX25T	1.74/0.27	N/A	2.03/0.27	N/A	ns
		XA6SLX45	1.58/0.29	N/A	1.87/0.29	N/A	ns
		XA6SLX45T	1.58/0.29	N/A	1.87/0.29	N/A	ns
		XA6SLX75	1.74/0.24	N/A	2.11/0.24	N/A	ns
		XA6SLX75T	1.74/0.24	N/A	2.11/0.24	N/A	ns
		XA6SLX100	N/A	N/A	2.64/0.82	N/A	ns
		XQ6SLX75	N/A	N/A	2.11/0.24	2.60/0.75	ns
		XQ6SLX75T	1.74/0.24	N/A	2.11/0.24	N/A	ns
		XQ6SLX150	N/A	N/A	1.67/0.70	2.57/0.97	ns
		XQ6SLX150T	1.50/0.70	N/A	1.67/0.70	N/A	ns

**Notes:**

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage. These measurements include CMT jitter; DCM CLK0 driving PLL, PLL CLKOUT0 driving BUFG.
2. IFF = Input Flip-Flop or Latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 79: Package Skew (Cont'd)

Symbol	Description	Device	Package <sup>(2)</sup>	Value	Units
$T_{PKGSKEW}$	Package Skew <sup>(1)</sup>	LX45	CSG324	70	ps
			CS(G)484	99	ps
			FG(G)484	109	ps
			FG(G)676	138	ps
		LX45T	CSG324	75	ps
			CS(G)484	100	ps
			FG(G)484	95	ps
		LX75	CS(G)484	101	ps
			FG(G)484	107	ps
			FG(G)676	161	ps
		LX75T	CS(G)484	107	ps
			FG(G)484	110	ps
			FG(G)676	134	ps
		LX100	CS(G)484	95	ps
			FG(G)484	155	ps
			FG(G)676	144	ps
		LX100T	CS(G)484	88	ps
			FG(G)484	111	ps
			FG(G)676	147	ps
			FG(G)900	134	ps
		LX150	CS(G)484	84	ps
			FG(G)484	103	ps
			FG(G)676	115	ps
			FG(G)900	121	ps
		LX150T	CS(G)484	83	ps
			FG(G)484	88	ps
			FG(G)676	141	ps
			FG(G)900	120	ps

**Notes:**

1. These values represent the worst-case skew between any two SelectIO resources in the package: shortest delay to longest delay from Pad to Ball.
2. Some of the devices are available in both Pb and Pb-free (additional G) packages as standard ordering options. See [DS160: Spartan-6 Family Overview](#) for more information.

Table 80: Sample Window

Symbol	Description	Device <sup>(1)</sup>	Speed Grade				Units
			-3	-3N	-2	-1L	
$T_{SAMP}$	Sampling Error at Receiver Pins <sup>(2)</sup>	All	510	510	530	740	ps
$T_{SAMP\_BUFI02}$	Sampling Error at Receiver Pins using BUFI02 <sup>(3)</sup>	All	430	430	450	590	ps

**Notes:**

1. LXT devices are not available with a -1L speed grade.
2. This parameter indicates the total sampling error of Spartan-6 FPGA DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the DCM to capture the DDR input registers' edges of operation. These measurements include:
  - CLK0 DCM jitter
  - DCM accuracy (phase offset)
  - DCM phase shift resolution
 These measurements do not include package or clock tree skew.
3. This parameter indicates the total sampling error of Spartan-6 FPGA DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the BUFI02 clock network and IODELAY2 to capture the DDR input registers' edges of operation. These measurements do not include package or clock tree skew.